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Distributions

... example, the **Weibull** distribution was formulated by Waloddi **Weibull** and thus ... terms of lifetime distributions, the location parameter represents a **time shift**. ...

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... To solve this **time-shift** problem, we need a modified **Weibull** function with an extra parameter, t_0 , which allows for time shifting as described in (12). ...

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... It is a **time shift** causing curvature on the **Weibull** graph for time scaling as originally recorded. The t_0 can also be used for other distributions. ...

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Summary List of Functions

... RANDOM **WEIBULL**(m, x, S, h, r, s) distributed between 0 and 1. ... **TIME SHIFT**(data, shift) Shifts data in time. **TIME TRANSITION**(T_1, \dots) Obsolete. ...

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... Wang (1996) C RP **Weibull** and log-logistic hazard. CCH (1997) D SP NL. ... proportional to departure **time shift** for earlier and later options. ...

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Time period choice modelling: a preliminary review

... is generally possible to measure the benefit from a **time shift** without knowing ... the error terms ϵ_i having independent and identical **Weibull** distributions, with ...

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... of heteroskedasticity between **time-shift** alternatives as a function of the size of the shift in time; • the relative values of η_E and η_L indicate whether ...

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... are calculated by relating the area under each best fit **Weibull** curve for ... purpose of the cross-correlation analysis was to estimate the **tim -shift** among the ...

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... Our **time-shift** technique produces a very robust dichotic pitch percept, and these stimuli are more similar to real localized ... **Weibull** function 21 with slope four ...

sirl.stanford.edu/~bob/pubs/pdfs/Dougherty_DPNdyslexia_NeuroReport98.pdf - [Similar pages](#)

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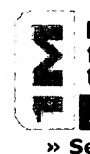
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... Initiated highly accelerated life testing for FIT/**MTBF** analysis (**HALT**, **HASS**) .

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